

EAST Search History

EAST Search History (Prior Art)

| Ref # | Hits | Search Query | DBs | Default Operator | Plurals | Time Stamp |
|-------|--------|---|---|------------------|---------|---------------------|
| L1 | 156 | wafer adj pad and inspection | US-PGRUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2010/03/10 16:04 |
| L2 | 27 | L1 and notch | US-PGRUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2010/03/10 16:04 |
| L3 | 337122 | crystallographic asj structure and wafer | US-PGRUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2010/03/10 16:09 |
| L4 | 966 | crystallographic adj structure and wafer | US-PGRUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2010/03/10 16:09 |
| L5 | 191 | crystallographic adj structure same wafer | US-PGRUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2010/03/10 16:09 |
| L6 | 150 | L5 and (@ad<"20040202" or @riad<"20040202" or @prad<"20040202" or @ptad<"20040202") | US-PGRUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2010/03/10 16:21 |
| L7 | 117 | L5 and @ad<"20040202" | US-PGRUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2010/03/10 16:21 |
| L8 | 16 | L7 and(solar adj cell or cell) | US-PGRUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2010/03/10 16:22 |
| L9 | 16 | L8 and (compar\$3 or match\$3) and wafer and(solar adj cell or cell) | US-PGRUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2010/03/10 16:23 |

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|-----|-----|---|---|----|-----|---------------------|
| L10 | 41 | crystallographic adj structure and wafer and ingot | US-PGRUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2010/03/10 16:39 |
| L11 | 5 | L10 and (compar\$3 or match \$3) and wafer and (solar adj cell or cell) | US-PGRUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2010/03/10 16:40 |
| L12 | 4 | L11 and @ad<"20040202" | US-PGRUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2010/03/10 16:40 |
| L13 | 110 | ((("4352948") or ("6161054") or ("5203005") or ("5287472") or ("5292677") or ("5485097") or ("6243308") or ("4435498") or ("4471483") or ("4493055") or ("4519035") or ("4543444") or ("4898835") or ("4999689") or ("5019736") or ("5024972") or ("5252507") or ("5265847") or ("5315130") or ("5362666") or ("5393617") or ("5478363") or ("5491665") or ("5536964") or ("5552243") or ("5619419") or ("5624771") or ("5656392") or ("5657284") or ("5698453") or ("5698342") or ("5716459") or ("5808947") or ("5821160") or ("5851693") or ("5926419") or ("6040912") or ("RE36644") or ("6046078") or ("6140140") or ("6161213") or ("6225167") or ("6330819") or ("4304641") or ("4338480") or ("4353160") or ("4385198") or ("4400221") or ("4400868") or (").pn.")).FN. | US-PGRUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | OFF | 2010/03/10 16:43 |
| L14 | 106 | L13 and (@ad<"20040202" or @rlad<"20040202" or @prad<"20040202" or @ptad<"20040202") | US-PGRUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2010/03/10 16:43 |
| L15 | 106 | L13 and @ad<"20040202" | US-PGRUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2010/03/10 16:43 |
| L16 | 0 | L15 and crystallographic adj structure and wafer and ingot | US-PGRUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2010/03/10 16:44 |

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| L17 | 0 | L15 and crystallographic adj structure and wafer and ingot | US-PGRUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2010/03/10 16:46 |
| L18 | 5 | L15 and inspect\$3 and (crystallographic adj structure or wafer or ingot or cells or cell) | US-PGRUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2010/03/10 17:05 |
| L19 | 4 | L18 and (compar\$3 or match \$3) and (solar adj cell or cell crystallographic adj structure or wafer or ingot or cells or cell) | US-PGRUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2010/03/10 17:06 |
| L20 | 4 | L19 and @ad< "20040202" | US-PGRUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2010/03/10 17:07 |
| L21 | 4742 | crystallographic adj structure | US-PGRUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2010/03/10 17:10 |
| L22 | 4328355 | (wafer\$1 or semiconductor or solar adj cell or cell) | US-PGRUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2010/03/10 17:11 |
| L23 | 98638 | L22 and inspect\$3 and (cells or cell) | US-PGRUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2010/03/10 17:20 |
| L24 | 153527 | L22 and inspect\$3 and (cells or cell or wafer or memory) | US-PGRUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2010/03/10 17:21 |
| L25 | 4742 | crystallographic adj structure | US-PGRUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2010/03/10 17:22 |
| L26 | 632 | L24 and L25 | US-PGRUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2010/03/10 17:27 |
| L27 | 1 | L26 and wafer adj image and cell adj image | US-PGRUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2010/03/10 17:28 |

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| L28 | 3 | inspect\$3 and solar adj cell and matrix and convert\$3 and electricity and solar adj cell and treating and silicon adj wafers and ingot | US-PGRUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2010/03/10 17:32 |
| L29 | 2 | L28 and @ad< "20040202" | US-PGRUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2010/03/10 17:33 |
| L30 | 1 | L28 and (compar\$3 or match \$3)and wafer adj image and cell adj image | US-PGRUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2010/03/10 17:39 |
| L31 | 1 | L25 and wafer adj image and cell adj image | US-PGRUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2010/03/10 17:40 |
| L32 | 17 | L22 and (compar\$3 or match \$3)and wafer adj image and cell adj image | US-PGRUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2010/03/10 17:40 |
| L33 | 3 | L32 and @ad< "20040202" | US-PGRUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2010/03/10 17:41 |
| L34 | 1 | L32 and crystallographic adj structure | US-PGRUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2010/03/10 17:51 |
| L35 | 1 | L32 and crystallographic adj structure and wafer adj structure and manufactured adj cell and crystallographic adj image and information and sufficient adj establish and correspondence and cell and wafer | US-PGRUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2010/03/10 17:58 |
| L36 | 1 | L32 and crystallographic adj structure and wafer adj structure and manufactured adj cell | US-PGRUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2010/03/10 17:59 |
| L37 | 1 | crystallographic adj structure and wafer adj structure and manufactured adj cell | US-PGRUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2010/03/10 17:59 |

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| L38 | 2 | L22 and crystallographic adj structure and manufactured adj cell | US-PGRUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2010/03/10 18:00 |
| L39 | 0 | L38 and @ad<"20040202" | US-PGRUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2010/03/10 18:01 |
| L40 | 1 | L25 and wafer adj image and cell adj image | US-PGRUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2010/03/10 18:04 |
| L41 | 607 | L25 and inspect\$3 and(cells or cell or memory) | US-PGRUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2010/03/10 18:06 |
| L42 | 1 | L41 and wafer adj image and cell adj image | US-PGRUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2010/03/10 18:06 |
| L43 | 587 | L41 and(compar\$3 or match \$3)and (memory or cell or memory adj cell) | US-PGRUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2010/03/10 18:07 |
| L44 | 1 | L41 and(compar\$3 or match \$3)same(memory or cell or memory adj cell)same wafer \$1 | US-PGRUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2010/03/10 18:08 |
| L45 | 1 | L43 and crystallographic adj structure and wafer adj structure and manufactured adj cell | US-PGRUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2010/03/10 18:09 |
| L46 | 1 | L43 and wafer adj structure and manufactured adj cell | US-PGRUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2010/03/10 18:09 |
| L47 | 1 | L43 and manufactured adj cell | US-PGRUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2010/03/10 18:10 |
| L48 | 297 | L43 and @ad<"20040202" | US-PGRUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2010/03/10 18:10 |

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| L49 | 12 | L48 and(compar\$3 or match \$3)and wafer and(solar adj cell or cell) | US-PGRUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2010/03/10 18:11 |
| L50 | 13 | L48 and inspect\$3 and wafer \$1 and(cells or cell or memory) | US-PGRUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2010/03/10 18:12 |
| L51 | 0 | L48 and inspect\$3 adj wafer \$1 same(cells or cell or memory) | US-PGRUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2010/03/10 18:13 |
| L52 | 0 | L48 and inspect\$3 adj wafer \$1 and(cells or cell or memory) | US-PGRUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2010/03/10 18:13 |
| L53 | 3559 | L21 and(wafer\$1 or semiconductor or solar adj cell or cell or memory) | US-PGRUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2010/03/10 18:14 |
| L54 | 2 | L53 and manufactured adj cell | US-PGRUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2010/03/10 18:14 |
| L55 | 0 | L54 and @ad<"20040202" | US-PGRUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2010/03/10 18:14 |
| L56 | 2 | L25 and manufactured adj cell | US-PGRUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2010/03/10 18:15 |
| L57 | 1818 | L25 and(wafer\$1 or semiconductor or memory) | US-PGRUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2010/03/10 18:16 |
| L58 | 237 | L25 and(wafer\$1 or semiconductor or memory)and inspect\$3 | US-PGRUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2010/03/10 18:16 |
| L59 | 119 | L58 and @ad<"20040202" | US-PGRUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2010/03/10 18:16 |

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| L60 | 12 | L59 and(compar\$3 or match\$3)and wafer and(solar adj cell or cell) | US-PGRUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2010/03/10 18:19 |
| L61 | 38 | L25 and inspect\$3 and(compar\$3 or match\$3)and wafer and (solar adj cell or cell) | US-PGRUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2010/03/10 18:28 |
| L62 | 41 | L25 and inspect\$3 and(compar\$3 or match\$3)and wafer and (solar adj cell or cell or memory) | US-PGRUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2010/03/10 18:29 |
| L63 | 13 | L62 and @ad<"20040202" | US-PGRUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2010/03/10 18:29 |
| L64 | 85837 | analyz\$3 and(crystalline or crystallographic adj structure) | US-PGRUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2010/03/10 18:35 |
| L65 | 18 | L64 and manufactured adj cell | US-PGRUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2010/03/10 18:36 |
| L66 | 1 | L65 and(wafer\$1 or semiconductor or memory)and inspect\$3 | US-PGRUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2010/03/10 18:36 |
| L67 | 1 | inspect\$3 and photovoltaic adj area and manufactured and crystalline adj cell | US-PGRUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2010/03/10 18:43 |
| L68 | 0 | L67 and @ad<"20040202" | US-PGRUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2010/03/10 18:44 |
| L69 | 0 | L65 and(imaging or cod or camera or CMOS or IR)and wafer adj image and cell adj image | US-PGRUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2010/03/10 18:46 |
| L70 | 0 | L64 and(imaging or cod or camera or CMOS or IR)and wafer adj image and cell adj image | US-PGRUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2010/03/10 18:47 |

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| L71 | 31037 | L64 and(imaging or cod or camera or CMOS or IR) | US-PGRUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2010/03/10 18:47 |
| L72 | 8 | L71 and manufactured adj cell | US-PGRUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2010/03/10 18:47 |
| L73 | 2 | L72 and @ad<"20040202" | US-PGRUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2010/03/10 18:48 |
| L74 | 2106 | L71 and(wafer\$1 or semiconductor\$1 or IC or intergrated adj circuit) and inspect\$3 | US-PGRUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2010/03/10 18:51 |
| L75 | 45 | L74 and(compar\$3 or match \$3)same(memory or cell or memory adj cell)same wafer \$1 | US-PGRUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2010/03/10 18:52 |
| L76 | 18 | L75 and @ad<"20040202" | US-PGRUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2010/03/10 18:52 |
| S1 | 2124 | sheela chawan.Xa. | US-PGRUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2010/03/09 15:40 |
| S2 | 2338 | sheela chawan.Xp. | US-PGRUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2010/03/09 15:46 |
| S3 | 2 | S1 and wafer adj polishing | US-PGRUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2010/03/09 15:46 |
| S4 | 2 | S2 and wafer adj polishing | US-PGRUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2010/03/09 15:47 |
| S5 | 22 | S1 and wafer adj inspection | US-PGRUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2010/03/09 15:48 |

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| S6 | 22 | S2 and wafer adj inspection | US-PGRUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2010/03/09 15:48 |
| S7 | 156 | wafer adj pad and inspection | US-PGRUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2010/03/09 16:05 |

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